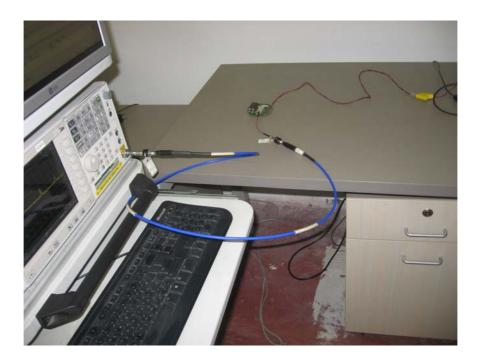


Photograph No.1 Setup for peak output power, OBW, conducted spurious emissions measurements



Photograph No.2 Setup for spurious emission measurements in the anechoic chamber below 30 MHz



Photograph No.3 Setup for spurious emission measurements in the anechoic chamber below 1000 MHz

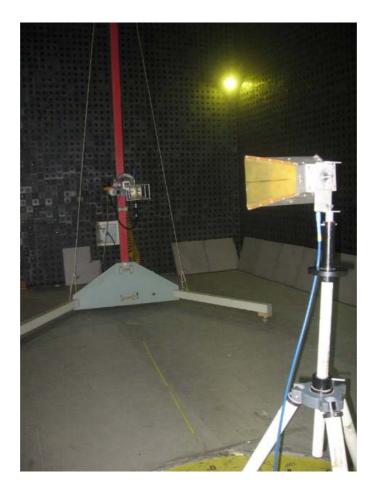


Photograph No.4 Setup for spurious emission measurements in the anechoic chamber above 1000 MHz

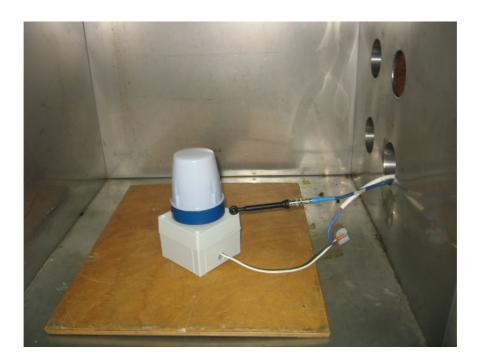




Photograph No.5 Setup for substitution ERP measurements of spurious below 1000 MHz



Photograph No.6 Setup for substitution ERP measurements of spurious above 1000 MHz



Photograph No.7 Setup for frequency stability measurements

Photograph No.8 Setup for transient frequency behaviour measurements